

Search Notes

Application/Control No.

10/661,638

Examiner

Lois Zheng

Applicant(s)/Patent under
Reexamination

HIRAIWA ET AL.

Art Unit

1742

SEARCHED

Class	Subclass	Date	Examiner
205	619	1/31/2006	LLZ
205	637	1/31/2006	LLZ
204	243.1	2/1/2006	LLZ
204	245-247	2/1/2006	LLZ
204	275.1	2/1/2006	LLZ

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventorship Search	1/31/2006	LLZ
See Attached EAST Search	2/1/2006	LLZ

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner